Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/714,654	TAKEKOSHI ET AL.	TAKEKOSHI ET AL.	
Examiner	Art Unit	Art Unit	
Randolph Chu	2624	2624	

	SEARCHED		
Class	Subclass	Date	Examiner
382	128	6/6/2007	RIC
705	2,3	6/6/2007	RIC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC		)
	DATE	EXMR
EAST	6/6/2007	RIC
Inventor Name search	6/6/2007	RIC
Consult with Wenpeng Chen	6/6/2007	RIC
Updated EAST Search	12/7/2007	RIC
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